

IN THE CLAIMS

Please replace claims 1, 5, and 13 with the amended claims below. A "marked up" version the amendment is included in **Attachment A**.

1. (Amended) A test fixture, comprising;

A3
SUB B1
a table moveable in a first direction, wherein the table is adapted to secure a substrate embodying a trace conductor having opposing ends terminating at respective opposing planar surfaces of the substrate; and

a probe pin moveable in two directions perpendicular to the first direction, wherein the probe pin is adapted to contact a first one of the opposing ends.

5. (Amended) A test fixture, comprising:

A4
SUB B1
a pin retainer for retaining only one upwardly extending pin;

a semiconductor substrate retainer having a trace conductor with one end of the trace conductor arranged above the pin; and

a mechanism for moving the pin retainer and semiconductor substrate in two dimensions for aligning the probe pin onto said one end of the trace conductor.

13. (Amended) A method for testing a semiconductor package, comprising:

A5
moving a substrate bearing a plurality of downwardly extending terminal ends of a trace conductor along an x-axis; and

moving an upwardly extending pin along a y-axis and a z-axis to make contact with only one of the plurality of downwardly extending terminal ends.